Product data sheet

1. General description

Planar passivated four quadrant triac in a SOT1292 (IITO3P) package intended for use in circuits where high static and dynamic dV/dt and high dI/dt can occur. This triac will commutate the full RMS current at the maximum rated junction temperature ($T_{j(max)}$ = 150 °C). It is used in applications where "high junction operating temperature capability" is required.

2. Features and benefits

- High current TRIAC
- Low thermal resistance
- High junction operating temperature capability (T_{i(max)} = 150 °C)
- High voltage capability
- Planar passivated for voltage ruggedness and reliability
- Insulated tab rated at 2500 V rms

3. Applications

- High current / high surge applications
- · High power / industrial controls -- e.g. heating, motors, lighting

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Values	Unit
Absolute	maximum rating			
V_{DRM}	repetitive peak off-state voltage		600	V
I _{T(RMS)}	RMS on-state current	square-wave pulse; T _{mb} ≤ 105 °C; Fig. 1; Fig. 2; Fig. 3	40	А
I _{TSM}	non-repetitive peak on- state current	full sine wave; $t_p = 20 \text{ ms}$; $T_{j(init)} = 25 \text{ °C}$; Fig. 4; Fig. 5	400	Α
		full sine wave; $t_p = 16.7 \text{ ms}$; $T_{j(init)} = 25 \text{ °C}$;	440	Α
T _j	junction temperature		150	°C

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics				•	
I _{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G + T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2-\text{ G-} $ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2- \text{ G+} $ $T_j = 25 \text{ °C; } Fig. 7$	-	-	70	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	-	80	mA
V_T on-state voltage I_T =		I _T = 56.6 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.2	1.5	V
Dynamic	characteristics					
dV _D /dt rate of rise of off-state voltage		V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit	750	-	-	V/µs
		V_{DM} = 536 V; T_j = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit	500	-	-	V/µs
dl _{com} /dt rate of change of commutating current		$V_D = 400 \text{ V}; T_j = 125 ^{\circ}\text{C}; I_{T(RMS)} = 20\text{A};$ $dV_{com}/dt = 20 \text{ V}/\mu\text{s}; gate open circuit}$	20	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 150 \text{ °C}; I_{T(RMS)} = 20\text{A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; gate open circuit}$	10	-	-	A/ms

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1		T2—T1
2	T2	main terminal 2		G sym051
3	G	gate		symoon
mb	n.c.	mounting base; isolated	IITO3P (SOT1292)	

6. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
BTA41-600B	IITO3P	plastic single-ended through-hole package; isolated heatsink mounted; 1 mounting hole; 3-lead TO3P	SOT1292			

7. Marking

Table 4. Marking codes

Type number	Marking codes
BTA41-600B	BTA41-600B

BTA41-600B

8. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Values	Unit
V_{DRM}	repetitive peak off-state voltage		600	V
I _{T(RMS)}	RMS on-state current	full sine wave; $T_{mb} \le 105^{\circ}C$; Fig. 1; Fig. 2; Fig. 3	40	А
I _{TSM}	non-repetitive peak on- state current	full sine wave; t_p = 20 ms; $T_{j(init)}$ = 25 °C; Fig. 4; Fig. 5	400	А
		full sine wave; $t_p = 16.7 \text{ ms}$; $T_{j(init)} = 25 \text{ °C}$;	440	А
l²t	I ² t for fusing	t _p = 10ms; sine wave	800	A²/s
dl _⊤ /dt	rate of rise of on-state current	I _G = 150mA	150	A/µs
I _{GM}	peak gate current	$t_p = 20 \mu s$	8	А
P _{GM}	peak gate power	t _p = 20µs	40	W
P _{G(AV)}	average gate power	over any 20 ms period	1	W
T _{stg}	storage temperature		-40 to 150	°C
T _j	junction temperature		150	°C

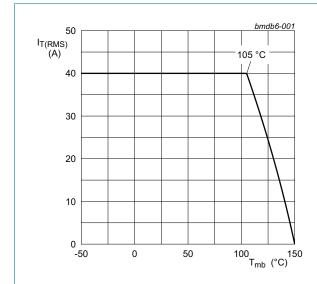


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values

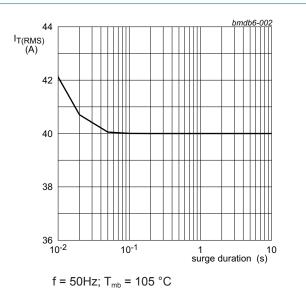


Fig. 2. RMS on-state current as a function of surge duration; maximum values

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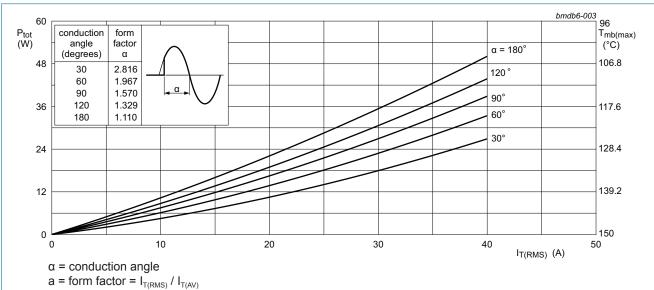


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

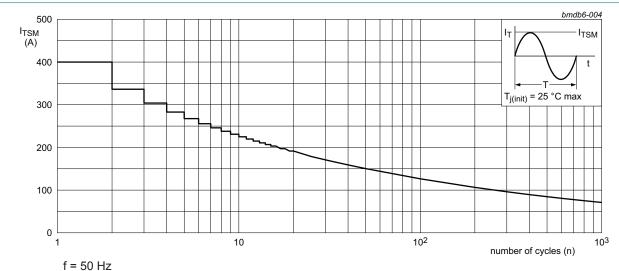
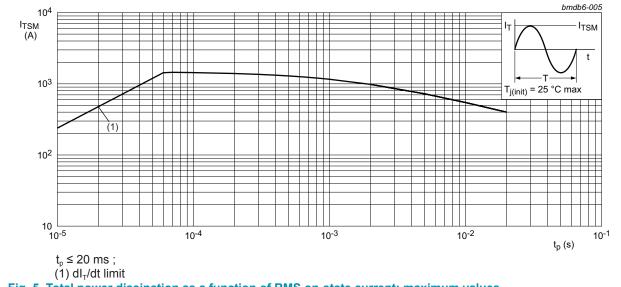


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



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9. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	Fig. 6	-	-	0.9	K/W
R _{th(j-a)}	thermal resistance from junction to ambient free air	in free air	-	55	-	K/W

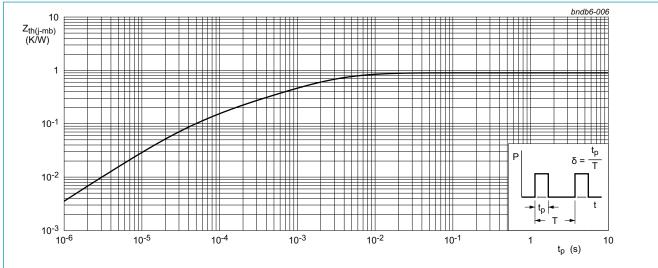


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

10. Isolation characteristics

Table 6. Isolation characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{isol(RMS)}	RMS isolation voltage	from all terminal to external heatsink; sinusoidal waveform; clean and dust free; 50 Hz \leq f \leq 60 Hz; RH \leq 65 %; $T_h = 25$ °C	-	-	2500	V

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11. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
I _{GT} gate trigger current		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;} $ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + \text{ G-;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2-\text{ G-;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2- \text{ G+;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$	-	-	70	mA
IL	latching current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G+;$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	100	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } \underline{Fig. 8}$	-	-	160	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	100	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2- \text{ G+;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 8}}$	-	-	100	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	-	80	mA
V _T	on-state voltage	I _T = 56.6 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.2	1.5	V
V _{GT} gate trigger voltage		age $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 ^{\circ}\text{C};$ Fig. 11		8.0	1.3	V
		$V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 150 \text{ °C};$ Fig. 11	0.2	0.45	-	V
I _D	off-state current	V _D = 600 V; T _j = 25 °C	-	-	10	μΑ
		V _D = 600 V; T _j = 150 °C	-	-	2.5	mA
Dynamic (characteristics		'			
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit	750	-	-	V/µs
		V_{DM} = 536 V; T_{j} = 150 °C; $(V_{DM}$ = 67% of V_{DRM}); exponential waveform; gate open circuit	500	-	-	V/µs
dI _{com} /dt	rate of change of commutating current	$V_D = 400 \text{ V; } T_j = 125 \text{ °C; } I_{T(RMS)} = 20\text{A;}$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s; gate open circuit}$	20	-	-	A/ms
		$V_D = 400 \text{ V; } T_j = 150 \text{ °C; } I_{T(RMS)} = 20\text{A;}$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s; gate open circuit}$	10	-	-	A/ms

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3

2

1

0

-50

ΙL

I_{L(25°C)}

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T_j (°C) 150

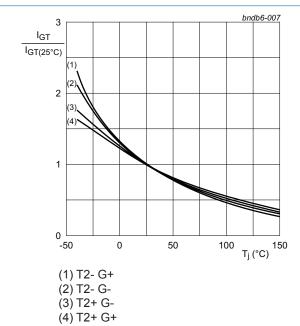


Fig. 8. Normalized latching current as a function of junction temperature

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Fig. 7. Normalized gate trigger current as a function of junction temperature

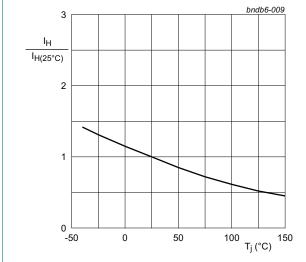
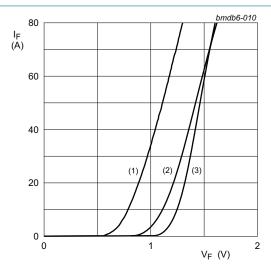


Fig. 9. Normalized holding current as a function of junction temperature



 $V_o = 1.063 \text{ V}; R_s = 0.0074 \Omega$

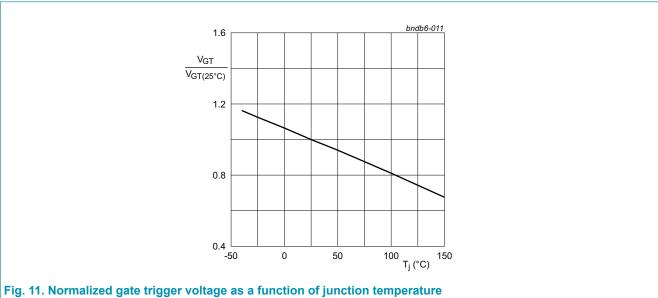
(1) $T_j = 150$ °C; typical values (2) $T_j = 150$ °C; maximum values

(3) $T_i = 25$ °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

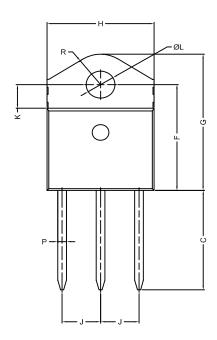
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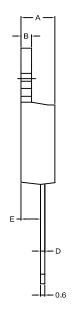
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12. Package outline







Unit		А	В	С	D	Ε	F	G	Н	٦	К	L	Р	R
mm	min	4.75	1.45	14.35	0.50	2.70	15.80	20.40	15.10	5.40	3.40	4.08	1.20	4.6
	max	4.95	1.55	15.60	0.70	2.90	16.50	21.10	15.50	5.65	3.65	4.17	1.40	(typ.)

VERSION IEC JEDEC EIAJ PROJECTION	-	OUTLINE						ISSUE DATE
SOT1292		VERSION	IEC	JEDEC	EIAJ		PROJECTION	1330E DATE
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13. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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For more information, please visit: http://www.ween-semi.com For sales office addresses, please send an email to: salesaddresses@ween-semi.com Date of release: 10 July 2017

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